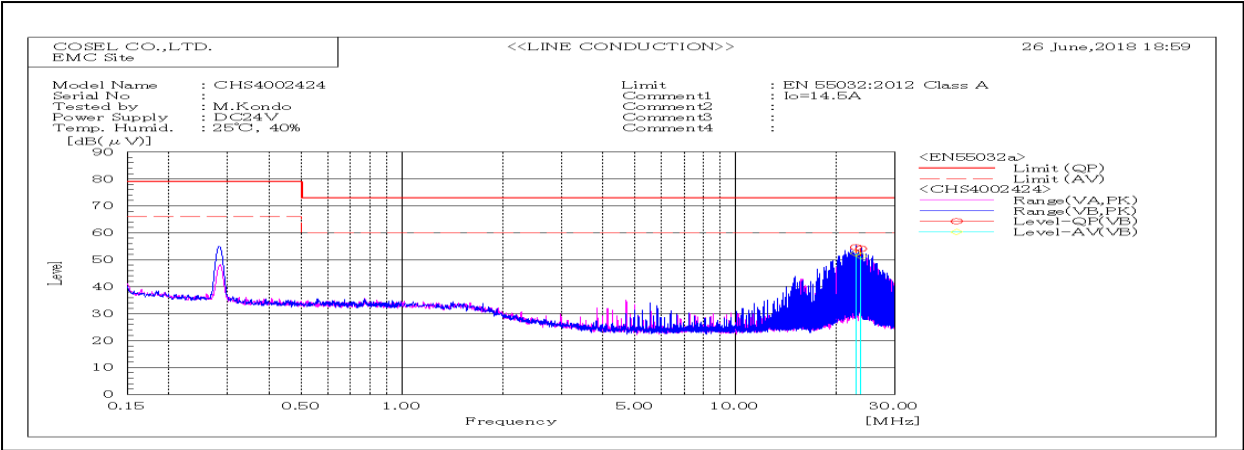
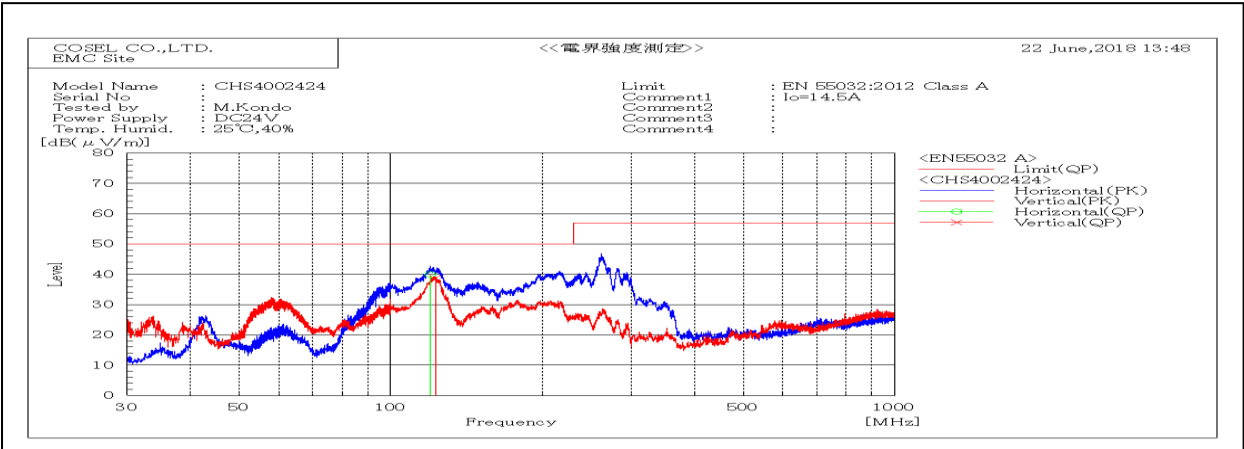


DATA SHEET		Date	26-Jun-18
Model	CHS4002424	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo



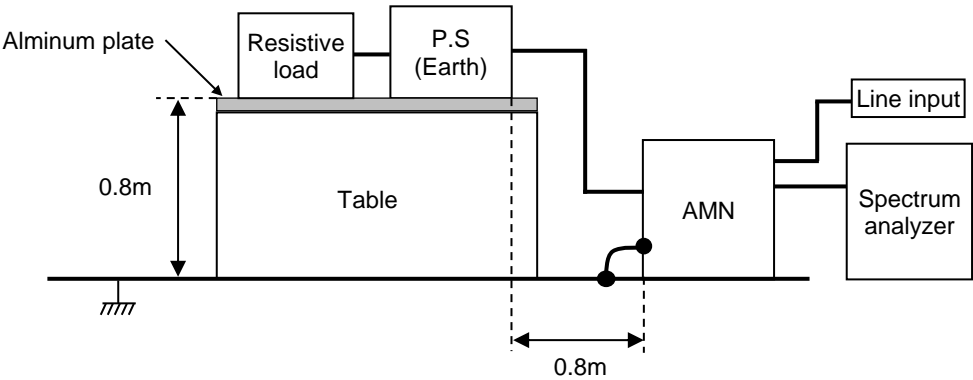
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
22.9293	VB	54.7	52.4	73	60	18.3	7.6	Pass	
23.7663	VB	54.1	51.4	73	60	18.9	8.6	Pass	



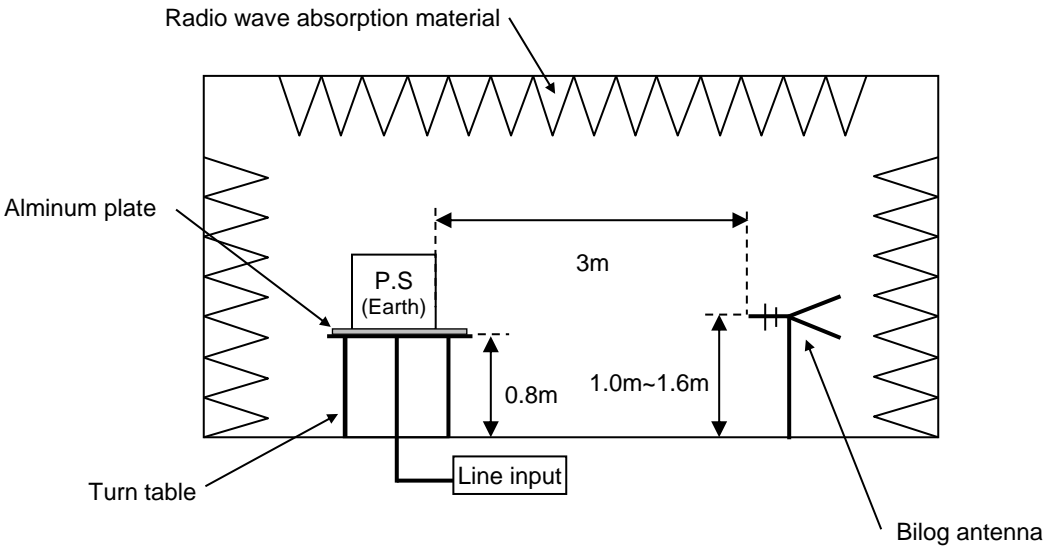
Frequency MHz	Polariz ation	Stabilit y	Reading dB(μV)	Limit dB(μV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
119.699	H	Stable	52.4	50	10	Pass	174	338	
122.713	V	Stable	54.6	50	11.3	Pass	147	283	

DATA SHEET		Date	26-Jun-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo

1. Line conduction



2. Radiated emission



## Conditions

Test : EMI  
Model Name : CHS40024□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

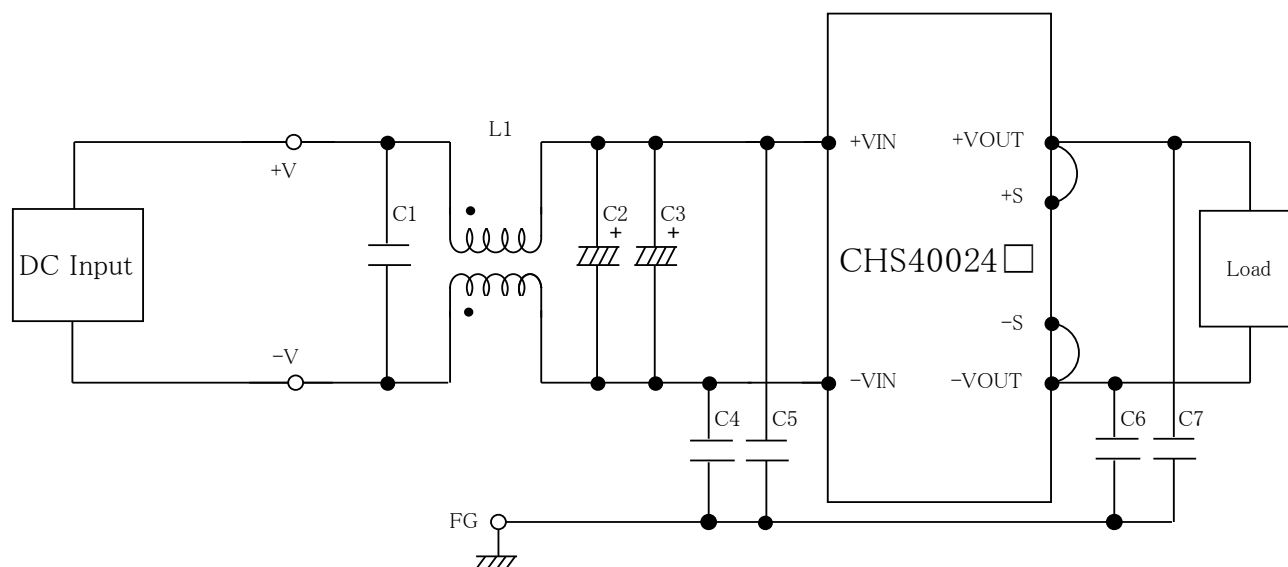


Fig.1 Testing circuitry

L1 : 1mH SC-30-100 (TOKIN)  
C1 : 250V 2.2  $\mu$ F FPD22E225J4 (NITSUKO)  
C2,C3 : 50V 330  $\mu$ F PWseries (nichicon)  
C4,C5 : 630V 0.068  $\mu$ F FPD22J683J4 (NITSUKO)  
C6,C7 : 630V 0.033  $\mu$ F FPD22J333J4 (NITSUKO)